

Resource Summary Report

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Delaware University Surface Analysis Core Facility

RRID:SCR_017796

Type: Tool

Proper Citation

Delaware University Surface Analysis Core Facility (RRID:SCR_017796)

Resource Information

URL: <http://www.udel.edu/chem/beebe/surface.htm>

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Description: Core provides consulting and services in X-ray Photoelectron Spectroscopy (XPS or ESCA), Time-of-Flight Secondary-Ion Mass Spectrometry (TOF-SIMS), X-ray Photoelectron Imaging, Auger Electron Spectroscopy (AES), Scanning Auger Microscopy or Imaging (SAM), Secondary-Electron Microscopy (SEM), Ion-Scattering Spectroscopy (ISS or LEIS), Scanning Probe Microscopy (STM and AFM).

Synonyms: Surface Analysis Facility

Resource Type: access service resource, core facility, service resource

Keywords: Surface, analysis, X-ray, photoelectron, spectroscopy, ion, mass, spectrometry, imaging, Auger, microscopy, scattering, scanning, probe, service, core

Funding: NSF

Availability: Open

Resource Name: Delaware University Surface Analysis Core Facility

Resource ID: SCR_017796

Alternate IDs: ABRF_439

Record Creation Time: 20220129T080337+0000

Record Last Update: 20260813T055154+0000

Ratings and Alerts

No rating or validation information has been found for Delaware University Surface Analysis Core Facility.

No alerts have been found for Delaware University Surface Analysis Core Facility.

Data and Source Information

Source: [SciCrunch Registry](#)

Usage and Citation Metrics

We have not found any literature mentions for this resource.